

# Hitachi S-530 Scanning Electron Microscope with X-ray NanoAnalysis



(Not Actual Picture)

The SEM can be used to examine surface details of solid materials. Internal surfaces can be exposed by sectioning or fracturing. It is equipped with a Evex EDS/EDX energy dispersive spectrometer which permits qualitative and quantitative compositional analysis. Image analysis software permits detection, measurement and analysis of features of interest; and elemental analysis establish the spatial position of the elemental composition.

Price - New  
\$ 230,00

AS-IS Price  
\$ 90,000

## Hitachi S-530 Scanning Electron Microscope-Pre-owned

(Original Manufacture Specification – Your results will Vary)

10 – 30 Kv - 10nm Resolution

Tungsten Filament

**No Warranty – Demonstration Available**

## Evex X-ray NanoAnalysis System – Pre-owned

Si(Li) X-ray Detector

Spectral Acquisition Module

Digital Imaging Module

Elemental Mapping Module

Advanced Features Module

Evex XP Workstation

**No Warranty – Demonstration Available**

**1 Year Factory Service Contract**

**FOB – Loading Dock**

**Customer Arranges for pickup/shipping/insurance**

**Installation – Please ask for separate quote**

**Evex**

**857 State Road**

**Princeton, NJ 08540**

**609-252-9192 Telephone**

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# Evex NanoAnalysis Features

## Image Acquisition Module

- Image Processing
- Image Analysis
- Image Operations
- Image Filters
- Thermal Imaging
- Image Measurement / Annotation
- Easy Report Writing
- AutoSave

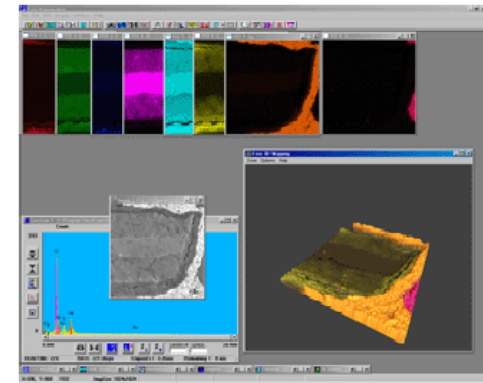


## Spectral Acquisition Module

- Spectral Processing
- Spectral Analysis
- Qualitative Analysis
- Quantitative Analysis
- Monte Carlo Simulation
- Detector Geometry Wizard
- Auto ID with Peak Labeling
- Auto Region of Interest (ROI)
- Automatic Calibration & Logging
- Easy Report Writing
- AutoSave

## Elemental Mapping

- Standard Elemental Mapping
- Ultra Fast Mapping
- Line Scan
- Point Mode & MultiPoint
- AutoAnalysis (Spectra at Every Pixel)
- ColorSEM - Quick Rendering
- Focus Mapping
- Thermal Mapping
- Easy Report Writing
- AutoSave



## Advanced Features

- Chemical Typing
- Trace Sensitive Analysis
- Critical Measurement
- 3D Mapping
- 3D Measurement
- AutoAnalysis (Spectra at Every Pixel)
- Remote Conferencing
- Stereo Imaging
- Synchro-Analysis